

<b>Notice of References Cited</b>	Application/Control No. 10/735,726		Applicant(s)/Patent Under Reexamination LEE, KYUNG-HA	
	Examiner AWET HAILE		Art Unit 2616	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,481,542 A	01-1996	Logston et al.	725/131
*	B	US-5,557,338 A	09-1996	Maze et al.	725/38
*	C	US-5,594,938 A	01-1997	Engel, Joel S.	725/139
*	D	US-6,330,436 B1	12-2001	Zidel, Andrew T.	455/412.2
*	E	US-6,370,391 B1	04-2002	Lietsalmi et al.	455/466
*	F	US-2002/0051442 A1	05-2002	Lee et al.	370/345
*	G	US-2003/0076812 A1	04-2003	Benedittis, Rosella De	370/350
*	H	US-2003/0137964 A1	07-2003	Suenaga et al.	370/342
*	I	US-6,741,293 B1	05-2004	Obuchi, Masashi	348/554
*	J	US-6,757,911 B1	06-2004	Shimoji et al.	725/136
*	K	US-2004/0187150 A1	09-2004	Gonder et al.	725/043
*	L	US-7,024,676 B1	04-2006	Klopfenstein, Scott E.	725/49
*	M	US-7,191,461 B1	03-2007	Arsenault et al.	725/54

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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